

**Notice of References Cited**

Application/Control No.

09/325,143

Applicant(s)/Patent Under  
Reexamination  
LEE, CHIN-HUI ET AL.

Examiner

Gerald Gauthier

Art Unit

2645

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	B	US-6,035,017	03-2000	Fenton et al.	379/88.04
	C	US-			
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	E	US-			
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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